(54) **Low drop voltage regulators with low quiescent current**

(57) A micropower low-dropout regulator (LDO) (30) having a low dropout voltage and a method of compensating base current errors. The new compensation technique involves placing a shunt capacitor (C_2) at a counterphase input (node A) of a Brokaw transconductance cell incorporating a base current compensation resistor (R_5).
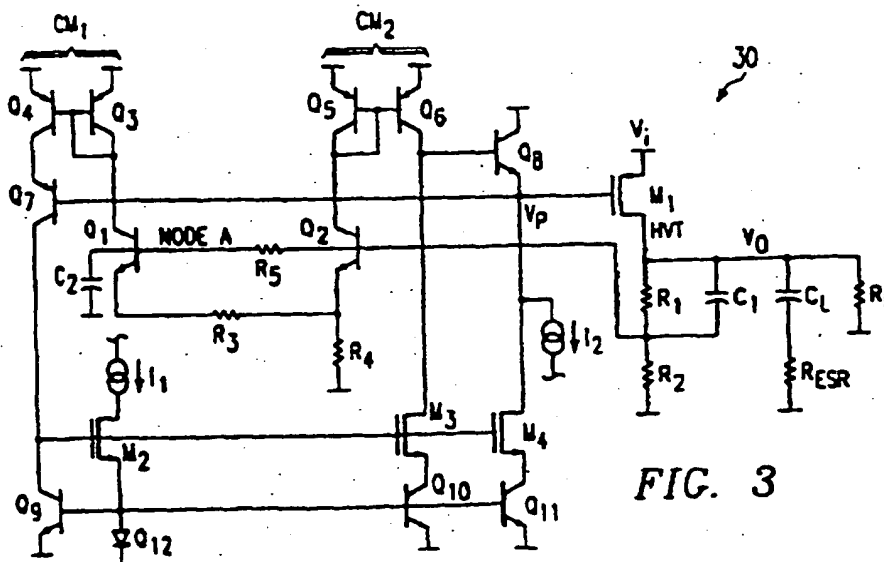
FIG. 3

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Description

FIELD OF THE INVENTION

[0001] The present invention is generally related to low-voltage regulator circuits, and more particularly low quiescent current regulators.

BACKGROUND OF THE INVENTION

[0002] The "dropout voltage" of a voltage regulator equals the minimum input-to-output voltage differential for which the circuit can maintain output regulation. Low-dropout (LDO) voltage regulators generally have dropout voltages of a few tenths of a volt at full rated current. In order to achieve such low dropout voltages, the circuit must use a PNP or PMOS pass element. Figure 1 shows a simplified block diagram of a typical prior art PMOS LDO circuit 10. The pass element is MOS transistor M_1, which is driven by amplifier A_1. The amplifier in turn receives the voltage generated by an internal voltage reference VR_1, and the voltage produced by a voltage divider network R_1-R_2. The circuit 10 is connected so that the amplifier achieves equilibrium when the voltage on the tap T of the voltage divider equals the voltage generated by the reference VR_1.

[0003] Many LDO applications require that the regulator consume little current to power its internal circuitry. This quiescent current typically equals 100μA for a modern PMOS LDO, and this changes little regardless of output current. The conventional topology of Figure 1 can be extended to provide low-current operation, typically down to 10μA. Lower currents require nonconventional circuit topologies.

[0004] The micropower LDO architecture contains multiple poles at relatively low frequencies, and therefore requires the insertion of compensating zeros to boost the phase, or otherwise the phase margin will deteriorate to the point that the circuit becomes unstable. These zeros are difficult to generate using integrated components because they must lie at relatively low frequencies (10-100kHz), they must not use large amounts of die area, and they must not consume any current. There are two basic techniques that have been used to insert zeros in this type of LDO architecture:

1) Placing a resistor Resr in series with the load capacitor C_L producing a zero at $w=1/(R_{esr} \times C_L)$. This can't make a low-frequency pole for a small capacitor value unless a large resistor R_{esr} is used, which is undesirable. Since micropower architectures have low bandwidth, they require low-frequency poles and this isn't a good solution - by itself.

2) Place a capacitor C (not shown) across the upper resistor R_1 of the feedback divider; this produces a zero at $w=1/(R_1 \times C)$. This doesn't work well for small divider ratios because the pole-zero separation becomes too small.

BRIEF DESCRIPTION OF THE DRAWINGS

[0005]

Figure 1 is a schematic diagram of a prior art low-dropout (LDO) voltage regulator based on a Brokaw transconductance cell;

Figure 2 is a schematic diagram of a Brokaw transconductance cell having a lower quiesent current by merging the amplifier and the voltage reference blocks into a single circuit with a minimum number of current limbs; and

Figure 3 is a schematic diagram of the present invention including a Brokaw transconductance cell having a base current compensation resistor and a capacitor producing a zero frequency, the capacitor effecting only the two transistors of the Brokaw cell.

SUMMARY OF THE INVENTION

[0006] The present invention achieves technical advantages as a micropower low-dropout voltage regulator having a shunt capacitor at the counterphase input of a Brokaw transconductance cell including a base current compensation resistor.

[0007] This resistor and capacitor provides a zero frequency that does not depend upon the attenuation ratio of the feedback divider. The counterphase compensation capacitor provides a low-frequency zero using a reasonably sized capacitor, providing a pole-zero separation that does not depend upon the attenuator ratio, and which requires no additional current-consuming components. The present invention can be combined with both feedback bypass compensation and ESR compensation to provide a wide-range phase boost capable of compensating a micropower LDO based upon the Brokaw transconductance cell. The configuration can be generally applied to any amplifier based on the Brokaw cell.

[0008] According to the preferred embodiment of the present invention, a voltage regulator produces an output signal and has a Brokaw cell comprising a first transistor and a second transistor. A compensation circuit is coupled to the Brokaw cell and generates a pole-zero pair in the Brokaw cell. Each of the first and second transistors have a base, wherein the compensation circuit comprises a base-current compensating resistor coupled between the first and second transistor bases. The compensation circuit also comprises a capacitor coupled to the compensating resistor.

[0009] The first and second transistors operate in counterphase to generate respective output signals 180° out-of-phase to one another. The compensation circuit is configured to provide a phase boost approaching 90° and which is independent of the output signal of the voltage regulator. The compensation circuit is configured to compensate the voltage regulator even when the regulator has a low feedback attenuation ratio.

[0010] The pole-zero pair defines a pole-zero separation, wherein the pole-zero separation is independent of attenuation ratio of the voltage regulator. The compensation circuit can be combined with a feedback bypass compensation circuit and an ESR compensation circuit to provide a wide-range phase boost. Preferably, the Brokaw cell is configured as an operational transconductance amplifier (OTA).

DETAILED DESCRIPTION OF THE PRIOR ART

[0011] One approach to reducing quiescent current consists of merging the amplifier and voltage reference blocks into a single circuit with a minimum number of current limbs. A class of operational transconductance amplifier (OTA) circuits based on the Brokaw transconductance cell fulfill this goal. Figure 2 shows the basic topology of such a circuit 20. The Brokaw transconductance cell consists of bipolar transistors Q_1 and Q_2 and resistors R_3 and R_4, shown at 22. The emitter area of transistor Q_1 is an integer multiple N of the emitter area of transistor Q_2. At equilibrium, where $I_{C1}=I_{C2}$, the voltage imposed across resistor R_3 equals:

$$V_{R3}=V_T \ln (N)$$

where V_T is the thermal voltage. The currents through transistors Q_1 and Q_2 are both imposed across R_4, so the voltage seen at the input of the Brokaw cell, V_{bg}, equals:

$$V_{bg} = V_{be2} + 2V_T \frac{R4}{R3} 1n(N)$$

This is the classic bandgap equation derived by Brokaw. If the input voltage to the cell is less than the equilibrium value V_{bg}, then $I_{C1} > I_{C2}$; if the input voltage is greater than V_{bg}, then $I_{C1} < I_{C2}$. The OTA architecture feeds the currents I_{C1} and I_{C2} into mirrors CM_1 and CM_2, and then uses another mirror CM_3 to invert the output of CM_1. Since CM_3 operates against CM_2, the current into or out of node V_p equals $I_{C2}-I_{C1}$, and this current equals zero only when the circuit rests at equilibrium. Any disturbance from equilibrium causes a current $I_{C2}-I_{C1}$ that seeks to restore equilibrium.

[0012] The OTA described above acts both as its own reference and as an amplifier, so it replaces components VR_1 and A_1 in Figure 1. Figure 2 shows how a complete LDO could be implemented around the OTA. This circuit has a very small number of current paths (five in all, four in the OTA and one in the resistor divider R_3 and R_4), making it a candidate for a micropower LDO.

[0013] Referring now to the present invention comprising circuit 30 in Figure 3, circuit 30 shows a practical implementation of a micropower LDO. Current mirrors CM_1 and CM_2 have been implemented as PNP transistors Q_3-Q_4 and transistors Q_5-Q_8. Current mirror CM_3

has been implemented as NPN transistors Q_9-Q_{10} with a MOS beta helper transistor M2 biased by diode-connected transistor Q_{12}. In order to prevent excessive current flow when transistor Q_{10} saturates, a current limiting component I_1 (typically a depletion-mode MOS transistor) has been inserted above the beta helper.

[0014] In order to minimize the impedance at node V_p, it is traditional to insert a follower stage, in this case consisting of emitter follower transistor Q_8 biased by a limb of the lower current mirror based on transistor Q_{11}. In order to obtain adequate headroom for transistor Q_8, transistor M_1 must have a high threshold voltage ($V_t > 1V$). This arrangement doesn't necessarily reduce the impedance at node V_p as much as desired because the output impedance of transistor Q_8 depends inversely upon its emitter current, and low currents therefore prevent one from taking full advantage of transistor Q_8. However, this stage is still necessary in order to allow proper implementation of a startup circuit, as will be explained below.

[0015] Because the Brokaw transconductance cell transistors Q_1-Q_2-R_3-R_4 has a very low transconductance, the OTA must have a relatively high output impedance. This is achieved in part by adding a cascode transistor M_3 to the output limb of the lower current mirror CM_3. This transistor can be biased from beta helper transistor M_1 due to the addition of diode transistor Q_{12}, which ensures that the current through transistors M_1 and M_2 have a definite relationship to one another (as would not be the case if this diode were omitted). A cascode on transistor Q_6 could provide a higher output impedance, but only at the price of degrading the already-minimal headroom of transistor Q_8. Figure 3 shows a better solution, consisting of a backside-cascode transistor Q_7 which holds the collector of transistor Q_4 at virtually the same voltage as the collector of transistor Q_6, thus eliminating most of the output voltage variations that low gain would otherwise produce.

[0016] As with most Brokaw-derived amplifiers, the OTA circuit 30 of Figure 3 has a secondary equilibrium point at zero bias. In order to perturb the circuit and ensure startup, a small current source I_2 has been added which pulls down on the gate of transistor M_1 to begin start-up. In practice, I_2 could be a depletion-mode transistor. In order to prevent this current from disturbing the OTA, an isolation stage must be inserted between the output of the OTA and node V_p; in this circuit emitter follower transistor Q_8 performs this function. Transistor M_4 has been added to balance the limbs of mirror CM_3, but is not absolutely necessary.

Compensating the Micropower LDO

[0017] LDO voltage regulators are notoriously difficult to compensate. The typical LDO (Figure 1) is dominated by two poles: a load pole formed by the load capacitance C_L, and a gate pole formed by the gate capacitance of transistor M_1 looking into the output impedance of am-

plifier A_1. In micropower LDO circuits, the extremely low currents used in the amplifier cause it to exhibit a very high output impedance. Consider the case of the amplifier of Figure 3, which uses an emitter-follower output stage biased at a current I_0, giving an output impedance of:

$$R_0 = \frac{V_T}{I_0}$$

which for a typical bias current I_0 of 0.5µA gives an output impedance of 52kΩ. The gate pole frequency f_g depends upon the gate capacitance C_g and equals:

$$f_g = \frac{1}{2\pi R_0 C_g}$$

assuming a typical gate capacitance of 100pF, the gate pole falls at 31kHz. The load pole falls at a frequency f_L:

$$f_L = \frac{1}{2\pi R_L C_L}$$

[0018] This pole can move through a wide range of frequencies, depending upon the load resistance R_L. Typically, the stability becomes poorest for the lowest R_L (in other words, at the highest currents). Under these conditions, f_L moves out to a higher frequency and approaches (or even exceeds) the frequency of the gate pole. For example, for $R_L = 30Ω$, $C_L = 1µF$; $f_L = 53kHz$. Given that f_g and f_L appear at nearly the same frequency, this system is virtually guaranteed to become unstable and to oscillate in the 30-50kHz band.

[0019] There are only two fundamental approaches to achieving stability: 1) push out the gate pole, and 2) insert zeros into the transfer function (lead compensation). Pushing out the gate pole to higher frequencies implies a reduction in the output impedance of amplifier A_1, which cannot be achieved without consuming larger currents or using smaller output transistors. This approach is therefore impractical in a micropower LDO, and some form of lead compensation must be used.

[0020] The two classical techniques of generating lead compensation in LDO's are the insertion of an ESR zero and the insertion of a feedback bypass capacitor. The ESR zero capacitor appears in Figure 1 as R_{esr}. This resistor generates a zero by operating against load capacitor C_L, and the resulting ESR zero appears at a frequency f_{esr}:

$$f_{esr} = \frac{1}{2\pi R_{esr} C_L}$$

[0021] Classically, stability is achieved by pushing out

the gate pole at least a decade from the load pole, and by then dropping the ESR zero onto the gate pole to achieve a pseudo-one-pole system. This cannot be done in micropower LDO's because the gate pole lies at too low a frequency, and the ESR zero cannot reach these low frequencies with practical values of ESR resistance. Most users object to more than 0.5Ω of ESR, and in combination with a 1µF load capacitor, the ESR can only reach down to about 300kHz, which is far above the 31kHz of the gate pole in the sample system discussed above.

[0022] The feedback bypass capacitor has better possibilities in micropower circuits. This capacitor appears in the circuit 30 of Figure 3 as capacitor C_1. Assuming the input impedance of the amplifier is "large", the transfer function V_0/V_I across the feedback divider is:

$$H = \frac{R_2}{\left(R_1 + R_2\right)} \frac{1 + S C_1 R_1}{1 + S C_1 \dfrac{R_1 R_2}{R_1 + R_2}}$$

which provides a compensation zero at f_z:

$$f_z = \frac{1}{2\pi C_1 R_1}$$

[0023] Given a typical value of R_1 of 1MΩ, a 5pF compensation capacitor would produce a zero at 32kHz, which is exactly the frequency of the gate pole discussed above. Unfortunately, this compensation technique has a limitation that becomes increasingly severe for lower-voltage regulators. The feedback bypass capacitor actually produces a lead-lag network, with a pole f_p at:

$$f_p = \frac{R_1 + R_2}{2\pi C_1 R_1 R_2}$$

[0024] The presence of this pole limits the range over which the zero can provide a phase boost, and therefore the magnitude of the phase boost. In practice, the pole-zero separation f_p/f_z should equal at least 3-5 to obtain good results from this circuit. The ratio f_p/f_z equals:

$$\frac{f_p}{f_z} = \frac{R_1 + R_2}{R_2}$$

[0025] The output voltage V_0 of the regulator is related to the Brokaw bandgap voltage V_{bg} by the formula:

$$V_o = V_{bg} \frac{R_1 + R_2}{R_2}$$

where V_{bg} = 1.25V or thereabouts for minimum temperature variation. This implies that the pole zero separation f_p/f_z equals:

$$\frac{f_p}{f_z} = 0.8 V_o$$

[0026] This implies that the feedback bypass capacitor doesn't provide much benefit for output voltages below 3V. Unfortunately, it is precisely these voltages that are of greatest importance in modern low-voltage applications. Therefore, the feedback bypass capacitor provides limited benefit. Many low-voltage LDO's still include feedback bypass capacitors because they neutralize the inevitable parasitic poles introduced by parasitic capacitance within the feedback divider.

[0027] Classical LDO designs generally combined ESR compensation with feedback bypass compensation. Such designs provided adequate performance so long as the output capacitor value and quiescent current remained relatively large. These conditions no longer universally apply.

Counterphase Compensation

[0028] According to the present invention, compensation of Brokaw transconductance cell arises from the inclusion of the Brokaw base-current compensating resistor R_5. This resistor cancels the error in output voltage caused by the base currents of transistors Q_1 and Q_2 flowing through divider R_1-R_2, providing that the value of R_5 equals:

$$R_5 = \frac{R_3}{R_4} \frac{R_1 R_2}{R_1 + R_2}$$

[0029] The present invention derives technical advantages by adding a capacitor C_2 that generates a pole-zero pair in the Brokaw transconductance cell. This can be explained intuitively as follows:

[0030] The current at the base of transistor Q_8 equals IC_2-IC_1, so transistors Q_1 and transistor Q_2 operate in counterphase. In other words, an input to transistor Q_1 will produce an output signal at node V_p 180° out-of-phase to the output signal generated in response to an input to transistor Q_2. Since a capacitor from the base of transistor Q_2 to ground would behave as a pole (90° phase lag), a capacitor from the base of transistor Q_1 to ground should produce a zero (90° phase lead). Resistor R_5 plays a vital role because it provides isolation between transistors Q_1 and Q_2 and allows the capacitor C_2 to affect only one of the two transistors Q_1 and Q_2.

One would intuitively expect the zero to depend upon resistors R_3 and R_4, since these lie in the ground path from capacitor C_2, and one would expect to find a pole dependent upon resistor R_5.

[0031] An analysis of the OTA transfer function with the addition of C_2 reveals the following pole and zero frequencies:

$$f_p = \frac{1}{2\pi R_5 C_2}$$

$$f_z = \frac{R_3}{2\pi R_5 \left(r_e + R_3 + 2R_4\right) C_2}$$

where r_e is the emitter resistance (V_T/I_C) of one of the Brokaw transistors Q_1-Q_2. Since resistors R_3 and r_e are both considerably smaller than $2R_4$, the zero frequency can be approximated as:

$$f_z \cong \frac{R_3}{4\pi R_5 R_4 C_2}$$

and the pole-zero separation f_p/f_z equals:

$$\frac{f_p}{f_z} \cong \frac{2R_4}{R_3}$$

[0032] One important conclusion can be immediately drawn from the above equation: to a first-order approximation, the pole-zero separation does not depend on R_1, R_2 or R_5. In practice, the ratio R_4/R_3 is forced to about six by the requirement that the Brokaw cell produce a bandgap voltage $V_{bg} \approx 1.25V$, the value required for temperature independence. This implies a pole-zero separation of about 12, providing a phase boost approaching 90° which is independent of the output voltage of the LDO. This is an extremely important result, as it shows that the counterphase compensation has a quality lacking in feedback bypass compensation, namely, the ability to compensate low-voltage regulators that have low attenuation ratios. The frequency of the zero actually depends upon R_1 and R_2, as can be seen by substituting equation of R_5 above into the equation for f_z above:

$$f_z = \frac{R_1 + R_2}{4\pi R_1 R_2 C_2}$$

[0033] The zero frequency does not depend upon the attenuator ratio, but does depend upon the parallel combination resistance $R_1 | | R_2$, which approaches R_1 for

low attenuator ratios. Even so, the value of C_2 can still be boosted to provide the necessary zero. A typical micropower regulator might have a parallel resistance R_1 || R_2 = 1 MΩ, and a 5pF compensation capacitor C_2 would provide a zero at 16kHz.

[0034] In summary, the counterphase compensation capacitor provides a low-frequency zero using a reasonably sized capacitor C_2, whose pole-zero separation does not depend upon attenuator ratio, and therefore is independent of output voltage, and which requires no additional current-consuming components. This technique can be combined with both feedback bypass compensation and ESR compensation to provide a wide-range phase boost capable of compensating a micropower LDO based upon the Brokaw transconductance cell. The illustrated circuit 30 uses an OTA configuration about the transconductance cell, but the technique is more general and can be applied to any amplifier based on the Brokaw cell.

[0035] Though the invention has been described with respect to a specific preferred embodiment, many variations and modifications will become apparent to those skilled in the art upon reading the present application. It is therefore the intention that the appended claims be interpreted as broadly as possible in view of the prior art to include all such variations and modifications.

Claims

1. A voltage regulator producing an output signal, comprising:

    a Brokaw cell comprising a first transistor (Q_1) and a second transistor (Q_2) ; and
    a compensation circuit (R_5, C_2) coupled to said Brokaw cell generating a pole-zero pair in said Brokaw cell.

2. The voltage regulator as specified in Claim 1 wherein each said first and second transistor (Q_1, Q_2) has a base, wherein said compensation circuit comprises a base-current compensating first resistor (R_5) coupled between said first and second transistor bases and a first capacitor (C_2) coupled to said compensating resistor.

3. The voltage regulator as specified in Claim 2 wherein each said transistor has an emitter further comprising a second resistor (R_3) coupled between said first and second transistor emitters, and a third resistor (R_4) coupled to said second resistor defining a voltage divide circuit.

4. The voltage regulator as specified in Claim 1 or 2 wherein said first and second transistors (Q_1, Q_2) operate in counterphase to generate respective output signals 180° out-of-phase to one another.

5. The voltage regulator as specified in Claim 1 wherein said compensation circuit is configured to provide a phase boost approaching 90° and which is independent of the output signal of the voltage regulator.

6. The voltage regulator as specified in Claim 1 wherein said compensation circuit is configured to compensate the voltage regulator even when having a low attenuation ratio.

7. The voltage regulator as specified in Claim 6 wherein said compensation circuit is configured to have a zero frequency that is independent of the attenuation ratio.

8. The voltage regulator as specified in Claim 1 wherein said pole-zero pair defines a pole-zero separation, wherein said pole-zero separation is independent of an attenuation ratio of the voltage regulator.

9. The voltage regulator as specified in Claim 1 further comprising a feedback bypass compensation circuit and an ESR compensation circuit providing a wide-range phase boost of said compensation circuit.

10. The voltage regulator as specified in Claim 1 or 2 wherein said Brokaw cell comprises a transconductance Brokaw cell.

11. The voltage regulator as specified in Claim 2 wherein said first resistor and said first capacitor produce a phase boost approaching 90°.

12. The voltage regulator as specified in Claim 11 wherein said phase boost is independent of the output signal of the voltage regulator.

13. The voltage regulator as specified in Claim 2 wherein said voltage regulator has an attenuation ratio, wherein said first resistor (R_5) and first capacitor (C_2) provide a zero frequency that is independent of the attenuation ratio.

14. The voltage regulator as specified in Claim 13 further comprising compensation circuitry generating a pole frequency, wherein said zero frequency and said pole frequency define a pole-zero separation.

15. The voltage regulator as specified in Claim 14 wherein said pole-zero separation is independent of the attenuation ratio.

16. The voltage regulator as specified in Claim 14 wherein said compensation circuitry comprises a feedback bypass compensation circuit and an ESR compensation circuit providing a wide-range phase boost of said compensation circuit.

17. The voltage regulator as specified in Claim 2 where-
    in said first resistor (R_5) and said first capacitor (C_2)
    are configured to compensate the voltage regulator
    having a low attenuation ratio.

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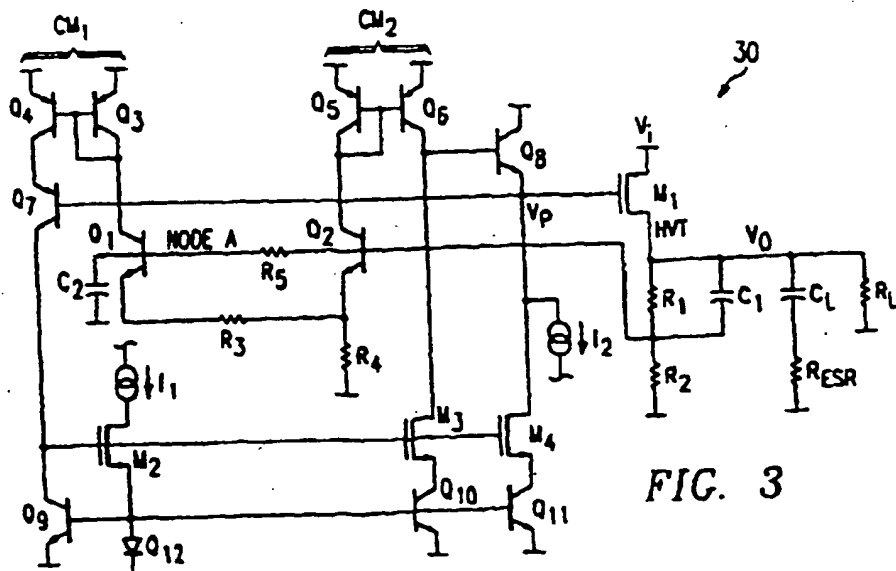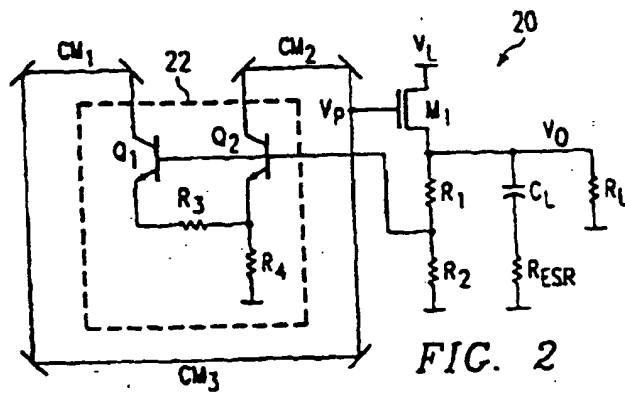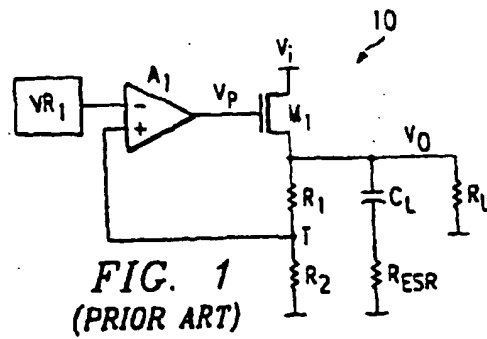20

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FIG. 1
(PRIOR ART)

FIG. 2

FIG. 3

European Patent
Office

EUROPEAN SEARCH REPORT

Application Number

EP 00 12 7218

DOCUMENTS CONSIDERED TO BE RELEVANT

Category	Citation of document with indication, where appropriate, of relevant passages	Relevant to claim	CLASSIFICATION OF THE APPLICATION (Int.Cl.7)
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A	* the whole document *	2-17	H03H11/12
A	US 5 325 070 A (MCGINN MICHAEL) 28 June 1994 (1994-06-28) * the whole document *	1-17	
A	US 5 774 021 A (ZANSKY ZOLTAN ET AL) 30 June 1998 (1998-06-30) * the whole document *	1-17	
A	US 4 789 819 A (NELSON CARL T) 6 December 1988 (1988-12-06) * abstract *	1-17	
A	US 4 851 953 A (O'NEILL DENNIS P ET AL) 25 July 1989 (1989-07-25) * abstract *	1-17	
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The present search report has been drawn up for all claims

Place of search	Date of completion of the search	Examiner
THE HAGUE	26 February 2001	Schobert, D

CATEGORY OF CITED DOCUMENTS

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